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### What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

### Applications of "[Embedded - Microcontrollers](#)"

#### Details

Product Status	Active
Core Processor	AVR
Core Size	8/16-Bit
Speed	32MHz
Connectivity	I <sup>2</sup> C, IrDA, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	50
Program Memory Size	192KB (96K x 16)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 3.6V
Data Converters	A/D 16x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-TQFP
Supplier Device Package	64-TQFP (14x14)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/microchip-technology/atxmega192d3-au">https://www.e-xfl.com/product-detail/microchip-technology/atxmega192d3-au</a>

**Table 32-25. External Clock with Prescaler <sup>(1)</sup> for System Clock**

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
1/t <sub>CK</sub>	Clock Frequency <sup>(2)</sup>	V <sub>CC</sub> = 1.6 - 1.8V	0		90	MHz
		V <sub>CC</sub> = 2.7 - 3.6V	0		142	
t <sub>CK</sub>	Clock Period	V <sub>CC</sub> = 1.6 - 1.8V	11			ns
		V <sub>CC</sub> = 2.7 - 3.6V	7			
t <sub>CH</sub>	Clock High Time	V <sub>CC</sub> = 1.6 - 1.8V	4.5			
		V <sub>CC</sub> = 2.7 - 3.6V	2.4			
t <sub>CL</sub>	Clock Low Time	V <sub>CC</sub> = 1.6 - 1.8V	4.5			
		V <sub>CC</sub> = 2.7 - 3.6V	2.4			
t <sub>CR</sub>	Rise Time (for maximum frequency)	V <sub>CC</sub> = 1.6 - 1.8V			1.5	
		V <sub>CC</sub> = 2.7 - 3.6V			1.0	
t <sub>CF</sub>	Fall Time (for maximum frequency)	V <sub>CC</sub> = 1.6 - 1.8V			1.5	
		V <sub>CC</sub> = 2.7 - 3.6V			1.0	
Δt <sub>CK</sub>	Change in period from one clock cycle to the next				10	%

- Notes:
1. System Clock Prescalers must be set so that maximum CPU clock frequency for device is not exceeded.
  2. The maximum frequency vs. supply voltage is linear between 1.6V and 2.7V, and the same applies for all other parameters with supply voltage conditions.

### 32.1.13.7 External 16MHz Crystal Oscillator and XOSC Characteristics

**Table 32-26. External 16MHz Crystal Oscillator and XOSC Characteristics**

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
	Cycle to cycle jitter	XOSCPWR=0	FRQRANGE=0	0		ns
			FRQRANGE=1, 2, or 3	0		
		XOSCPWR=1		0		
	Long term jitter	XOSCPWR=0	FRQRANGE=0	0		
			FRQRANGE=1, 2, or 3	0		
		XOSCPWR=1		0		
	Frequency error	XOSCPWR=0	FRQRANGE=0	0.03		%
			FRQRANGE=1	0.03		
			FRQRANGE=2 or 3	0.03		
		XOSCPWR=1		0.003		
	Duty cycle	XOSCPWR=0	FRQRANGE=0	50		
			FRQRANGE=1	50		
			FRQRANGE=2 or 3	50		
		XOSCPWR=1		50		

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
R <sub>Q</sub>	Negative impedance <sup>(1)</sup>	XOSCPWR=0, FRQRANGE=0	0.4MHz resonator, CL=100pF	44k		Ω
			1MHz crystal, CL=20pF	67k		
			2MHz crystal, CL=20pF	67k		
		XOSCPWR=0, FRQRANGE=1, CL=20pF	2MHz crystal	82k		
			8MHz crystal	1500		
			9MHz crystal	1500		
		XOSCPWR=0, FRQRANGE=2, CL=20pF	8MHz crystal	2700		
			9MHz crystal	2700		
			12MHz crystal	1000		
		XOSCPWR=0, FRQRANGE=3, CL=20pF	9MHz crystal	3600		
			12MHz crystal	1300		
			16MHz crystal	590		
		XOSCPWR=1, FRQRANGE=0, CL=20pF	9MHz crystal	390		
			12MHz crystal	50		
			16MHz crystal	10		
R <sub>Q</sub>	Negative impedance <sup>(1)</sup>	XOSCPWR=1, FRQRANGE=1, CL=20pF	9MHz crystal	1500		
			12MHz crystal	650		
			16MHz crystal	270		
		XOSCPWR=1, FRQRANGE=2, CL=20pF	12MHz crystal	1000		
			16MHz crystal	440		
		XOSCPWR=1, FRQRANGE=3, CL=20pF	12MHz crystal	1300		
			16MHz crystal	590		
	ESR	SF = safety factor			min(R <sub>Q</sub> )/SF	kΩ
	Start-up time	XOSCPWR=0, FRQRANGE=0	0.4MHz resonator, CL=100pF	1.0		ms
		XOSCPWR=0, FRQRANGE=1	2MHz crystal, CL=20pF	2.6		
		XOSCPWR=0, FRQRANGE=2	8MHz crystal, CL=20pF	0.8		
		XOSCPWR=0, FRQRANGE=3	12MHz crystal, CL=20pF	1.0		
		XOSCPWR=1, FRQRANGE=3	16MHz crystal, CL=20pF	1.4		

### 32.2.3 Current Consumption

**Table 32-33. Current Consumption for Active Mode and Sleep Modes**

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
I <sub>CC</sub>	Active power consumption <sup>(1)</sup>	32kHz, Ext. Clk	V <sub>CC</sub> = 1.8V	50		μA
			V <sub>CC</sub> = 3.0V	130		
		1MHz, Ext. Clk	V <sub>CC</sub> = 1.8V	215		
			V <sub>CC</sub> = 3.0V	475		
		2MHz, Ext. Clk	V <sub>CC</sub> = 1.8V	445	600	mA
			V <sub>CC</sub> = 3.0V	0.95	1.5	
	Idle power consumption <sup>(1)</sup>	32kHz, Ext. Clk	V <sub>CC</sub> = 1.8V	2.8		μA
			V <sub>CC</sub> = 3.0V	3		
		1MHz, Ext. Clk	V <sub>CC</sub> = 1.8V	46		
			V <sub>CC</sub> = 3.0V	92		
		2MHz, Ext. Clk	V <sub>CC</sub> = 1.8V	93	225	mA
			V <sub>CC</sub> = 3.0V	184	350	
	Power-down power consumption	T = 25°C	V <sub>CC</sub> = 3.0V	0.07	1.0	μA
				1.3	5.0	
				4.0	8.0	
		WDT and sampled BOD enabled, T = 25°C	V <sub>CC</sub> = 3.0V	1.3	2.0	
		WDT and sampled BOD enabled, T = 85°C		2.6	6.0	
		WDT and sampled BOD enabled, T = 105°C		5.0	10	
	Power-save power consumption <sup>(2)</sup>	RTC from ULP clock, WDT and sampled BOD enabled, T = 25°C	V <sub>CC</sub> = 1.8V	1.7		
			V <sub>CC</sub> = 3.0V	1.8		
		RTC from 1.024kHz low power 32.768kHz TOSC, T = 25°C	V <sub>CC</sub> = 1.8V	0.5	2.0	
			V <sub>CC</sub> = 3.0V	0.7	2.0	
		RTC from low power 32.768kHz TOSC, T = 25°C	V <sub>CC</sub> = 1.8V	0.9	3.0	
			V <sub>CC</sub> = 3.0V	1.2	3.0	
	Reset power consumption	Current through $\overline{\text{RESET}}$ pin subtracted	V <sub>CC</sub> = 3.0V	120		

- Notes:
1. All Power Reduction Registers set.
  2. Maximum limits are based on characterization, and not tested in production.



Table 32-63. Current Consumption for Modules and Peripherals

Symbol	Parameter	Condition <sup>(1)</sup>	Min.	Typ.	Max.	Units
I <sub>CC</sub>	ULP oscillator			0.9		μA
	32.768kHz int. oscillator			26		
	2MHz int. oscillator			79		
		DFLL enabled with 32.768kHz int. osc. as reference		110		
	32MHz int. oscillator			245		
		DFLL enabled with 32.768kHz int. osc. as reference		415		
	PLL	20× multiplication factor, 32MHz int. osc. DIV4 as reference		305		
	Watchdog timer			1.0		
	BOD	Continuous mode		138		
		Sampled mode, includes ULP oscillator		1.4		
	Internal 1.0V reference			185		mA
	Temperature sensor			173		
	ADC	16ksps V <sub>REF</sub> = Ext. ref.		1.3		
			CURRLIMIT = LOW	1.15		
			CURRLIMIT = MEDIUM	1.0		
			CURRLIMIT = HIGH	0.9		
		75ksps V <sub>REF</sub> = Ext. ref.	CURRLIMIT = LOW	1.7		
		300ksps V <sub>REF</sub> = Ext. ref.		3.1		
	USART	Rx and Tx enabled, 9600 BAUD		7.5		μA
	Flash memory and EEPROM programming			4		mA

Note: 1. All parameters measured as the difference in current consumption between module enabled and disabled. All data at V<sub>CC</sub> = 3.0V, Clk<sub>SYS</sub> = 1MHz external clock without prescaling, T = 25°C unless other conditions are given.

### 32.4.13 Clock and Oscillator Characteristics

#### 32.4.13.1 Calibrated 32.768kHz Internal Oscillator Characteristics

Table 32-106. 32.768kHz Internal Oscillator Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
	Frequency			32.768		kHz
	Factory calibration accuracy	T = 85°C, V <sub>CC</sub> = 3.0V	-0.5		0.5	%
	User calibration accuracy		-0.5		0.5	

#### 32.4.13.2 Calibrated 2MHz RC Internal Oscillator Characteristics

Table 32-107. 2MHz Internal Oscillator Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
	Frequency range	DFLL can tune to this frequency over voltage and temperature	1.8	2.0	2.2	MHz
	Factory calibrated frequency			2.0		
	Factory calibration accuracy	T = 85°C, V <sub>CC</sub> = 3.0V	-1.5		1.5	%
	User calibration accuracy		-0.2		0.2	
	DFLL calibration stepsize			0.18		

#### 32.4.13.3 Calibrated 32MHz Internal Oscillator Characteristics

Table 32-108. 32MHz Internal Oscillator Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
	Frequency range	DFLL can tune to this frequency over voltage and temperature	30	32	55	MHz
	Factory calibrated frequency			32		
	Factory calibration accuracy	T = 85°C, V <sub>CC</sub> = 3.0V	-1.5		1.5	%
	User calibration accuracy		-0.2		0.2	
	DFLL calibration step size			0.19		

#### 32.4.13.4 32kHz Internal ULP Oscillator Characteristics

Table 32-109. 32kHz Internal ULP Oscillator Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
	Factory calibrated frequency			32		kHz
	Factory calibration accuracy	T = 85°C, V <sub>CC</sub> = 3.0V	-12		12	%
	Accuracy		-30		30	

## 32.5 Atmel ATxmega256D3

### 32.5.1 Absolute Maximum Ratings

Stresses beyond those listed in [Table 32-117](#) may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

**Table 32-117. Absolute Maximum Ratings**

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
$V_{CC}$	Power supply voltage		-0.3		4	V
$I_{VCC}$	Current into a $V_{CC}$ pin				200	mA
$I_{GND}$	Current out of a Gnd pin				200	
$V_{PIN}$	Pin voltage with respect to Gnd and $V_{CC}$		-0.5		$V_{CC} + 0.5$	V
$I_{PIN}$	I/O pin sink/source current		-25		25	mA
$T_A$	Storage temperature		-65		150	°C
$T_J$	Junction temperature				150	

### 32.5.2 General Operating Ratings

The device must operate within the ratings listed in [Table 32-118](#) in order for all other electrical characteristics and typical characteristics of the device to be valid.

**Table 32-118. General Operating Conditions**

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
$V_{CC}$	Power supply voltage		1.60		3.6	V
$AV_{CC}$	Analog supply voltage		1.60		3.6	
$T_A$	Temperature range		-40		85	°C
$T_J$	Junction temperature		-40		105	

**Table 32-119. Operating Voltage and Frequency**

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
$Clk_{CPU}$	CPU clock frequency	$V_{CC} = 1.6V$	0		12	MHz
		$V_{CC} = 1.8V$	0		12	
		$V_{CC} = 2.7V$	0		32	
		$V_{CC} = 3.6V$	0		32	

The maximum CPU clock frequency depends on  $V_{CC}$ . As shown in [Figure 32-29 on page 140](#) the frequency vs.  $V_{CC}$  curve is linear between  $1.8V < V_{CC} < 2.7V$ .

Table 32-121. Current Consumption for Modules and Peripherals

Symbol	Parameter	Condition <sup>(1)</sup>	Min.	Typ.	Max.	Units
I <sub>CC</sub>	ULP oscillator			0.9		μA
	32.768kHz int. oscillator			25		
	2MHz int. oscillator			78		
		DFLL enabled with 32.768kHz int. osc. as reference		110		
	32MHz int. oscillator			250		
		DFLL enabled with 32.768kHz int. osc. as reference		440		
	PLL	20× multiplication factor, 32MHz int. osc. DIV4 as reference		310		
	Watchdog timer			1.0		
	BOD	Continuous mode		132		
		Sampled mode, includes ULP oscillator		1.4		
	Internal 1.0V reference			185		mA
	Temperature sensor			182		
	ADC	16ksps V <sub>REF</sub> = Ext. ref.		1.12		
			CURRLIMIT = LOW	1.01		
			CURRLIMIT = MEDIUM	0.9		
			CURRLIMIT = HIGH	0.8		
		75ksps V <sub>REF</sub> = Ext. ref.	CURRLIMIT = LOW	1.7		
		300ksps V <sub>REF</sub> = Ext. ref.		3.1		
	USART	Rx and Tx enabled, 9600 BAUD		9.5		μA
	Flash memory and EEPROM programming			10		mA

Note: 1. All parameters measured as the difference in current consumption between module enabled and disabled. All data at V<sub>CC</sub> = 3.0V, Clk<sub>SYS</sub> = 1MHz external clock without prescaling, T = 25°C unless other conditions are given.

### 32.5.8 Bandgap and Internal 1.0V Reference Characteristics

**Table 32-129. Bandgap and Internal 1.0V Reference Characteristics**

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
	Startup time	As reference for ADC	1 Clk <sub>PER</sub> + 2.5μs			μs
		As input voltage to ADC and AC		1.5		
	Bandgap voltage			1.1		V
INT1V	Internal 1.00V reference	T = 85°C, after calibration	0.99	1.0	1.01	
	Variation over voltage and temperature	Calibrated at T = 85°C		1		

### 32.5.9 Brownout Detection Characteristics

**Table 32-130. Brownout Detection Characteristics <sup>(1)</sup>**

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
V <sub>BOT</sub>	BOD level 0 falling V <sub>CC</sub>		1.40	1.60	1.70	V
	BOD level 1 falling V <sub>CC</sub>			1.8		
	BOD level 2 falling V <sub>CC</sub>			2.0		
	BOD level 3 falling V <sub>CC</sub>			2.2		
	BOD level 4 falling V <sub>CC</sub>			2.4		
	BOD level 5 falling V <sub>CC</sub>			2.6		
	BOD level 6 falling V <sub>CC</sub>			2.8		
	BOD level 7 falling V <sub>CC</sub>			3.0		
t <sub>BOD</sub>	Detection time	Continuous mode		0.4		μs
		Sampled mode		1000		
V <sub>HYST</sub>	Hysteresis			1.0		%

Note: 1. BOD is calibrated at 85°C within BOD level 0 values, and BOD level 0 is the default level.

### 32.5.10 External Reset Characteristics

**Table 32-131. External Reset Characteristics**

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
t <sub>EXT</sub>	Minimum reset pulse width		1000	90		ns
V <sub>RST</sub>	Reset threshold voltage	V <sub>CC</sub> = 2.7 - 3.6V		0.45 * V <sub>CC</sub>		V
		V <sub>CC</sub> = 1.6 - 2.7V		0.45 * V <sub>CC</sub>		
R <sub>RST</sub>	Reset pin pull-up resistor			25		kΩ

### 32.5.13.5 Internal Phase Locked Loop (PLL) Characteristics

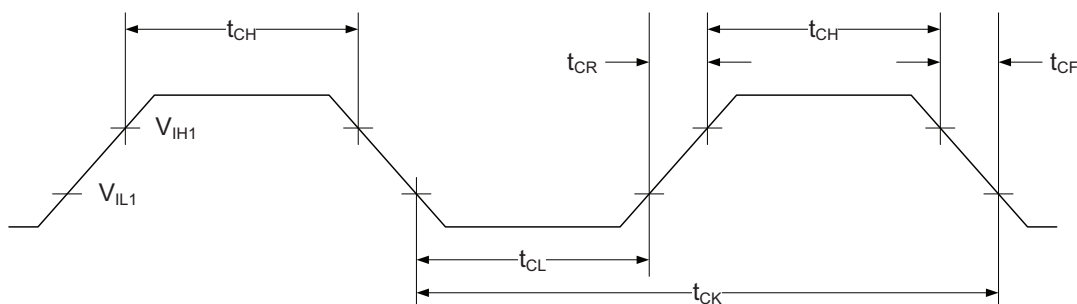
**Table 32-139. Internal PLL Characteristics**

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
$f_{IN}$	Input frequency	Output frequency must be within $f_{OUT}$	0.4		64	MHz
$f_{OUT}$	Output frequency <sup>(1)</sup>	$V_{CC} = 1.6 - 1.8V$	20		48	
		$V_{CC} = 2.7 - 3.6V$	20		128	
	Start-up time			25		$\mu s$
	Re-lock time			25		

Note: 1. The maximum output frequency vs. supply voltage is linear between 1.8V and 2.7V, and can never be higher than four times the maximum CPU frequency.

### 32.5.13.6 External Clock Characteristics

**Figure 32-31. External Clock Drive Waveform**



**Table 32-140. External Clock used as System Clock without Prescaling**

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
$1/t_{CK}$	Clock Frequency <sup>(1)</sup>	$V_{CC} = 1.6 - 1.8V$	0		12	MHz
		$V_{CC} = 2.7 - 3.6V$	0		32	
$t_{CK}$	Clock Period	$V_{CC} = 1.6 - 1.8V$	83.3			ns
		$V_{CC} = 2.7 - 3.6V$	31.5			
$t_{CH}$	Clock High Time	$V_{CC} = 1.6 - 1.8V$	30.0			
		$V_{CC} = 2.7 - 3.6V$	12.5			
$t_{CL}$	Clock Low Time	$V_{CC} = 1.6 - 1.8V$	30.0			
		$V_{CC} = 2.7 - 3.6V$	12.5			
$t_{CR}$	Rise Time (for maximum frequency)	$V_{CC} = 1.6 - 1.8V$			10	
		$V_{CC} = 2.7 - 3.6V$			3	
$t_{CF}$	Fall Time (for maximum frequency)	$V_{CC} = 1.6 - 1.8V$			10	
		$V_{CC} = 2.7 - 3.6V$			3	
$\Delta t_{CK}$	Change in period from one clock cycle to the next				10	%

Note: 1. The maximum frequency vs. supply voltage is linear between 1.6V and 2.7V, and the same applies for all other parameters with supply voltage conditions.

33.1.7 External Reset Characteristics

Figure 33-49. Minimum Reset Pin Pulse Width vs.  $V_{CC}$

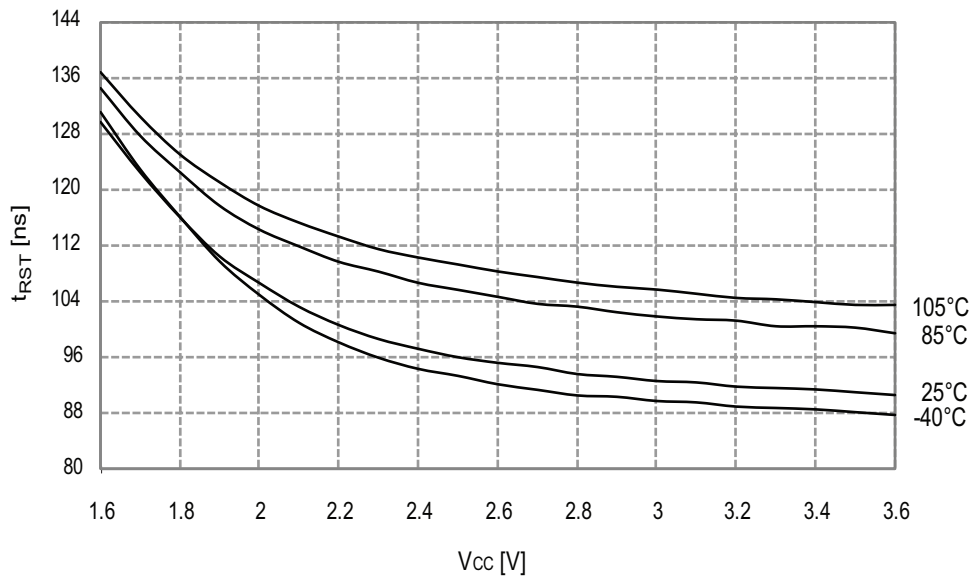
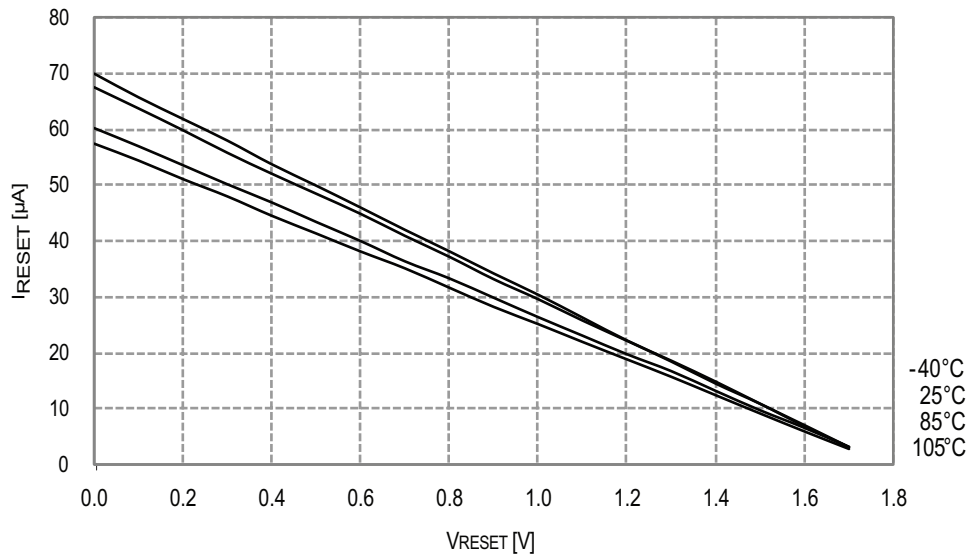
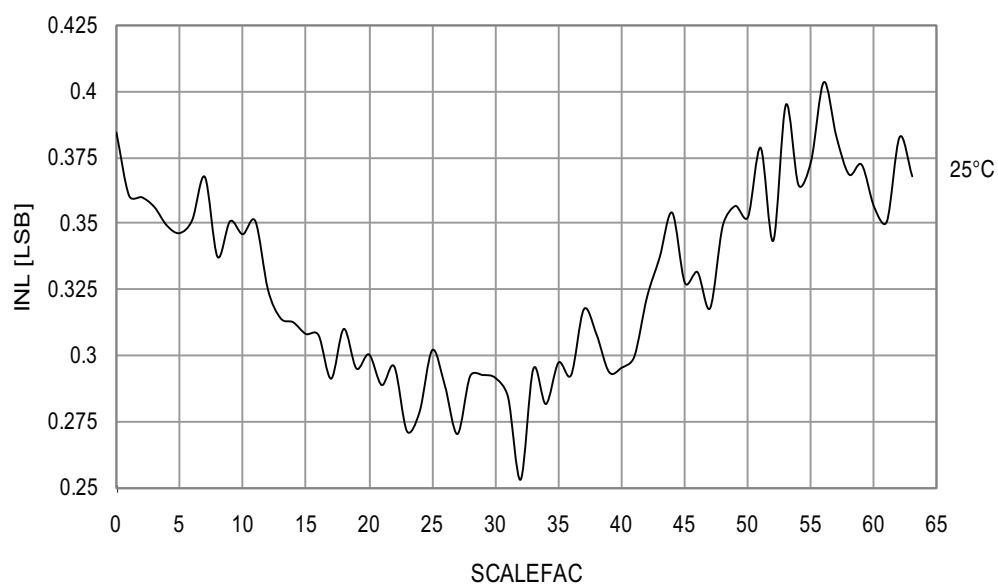


Figure 33-50. Reset Pin Pull-up Resistor Current vs. Reset Pin Voltage  
 $V_{CC} = 1.8V$



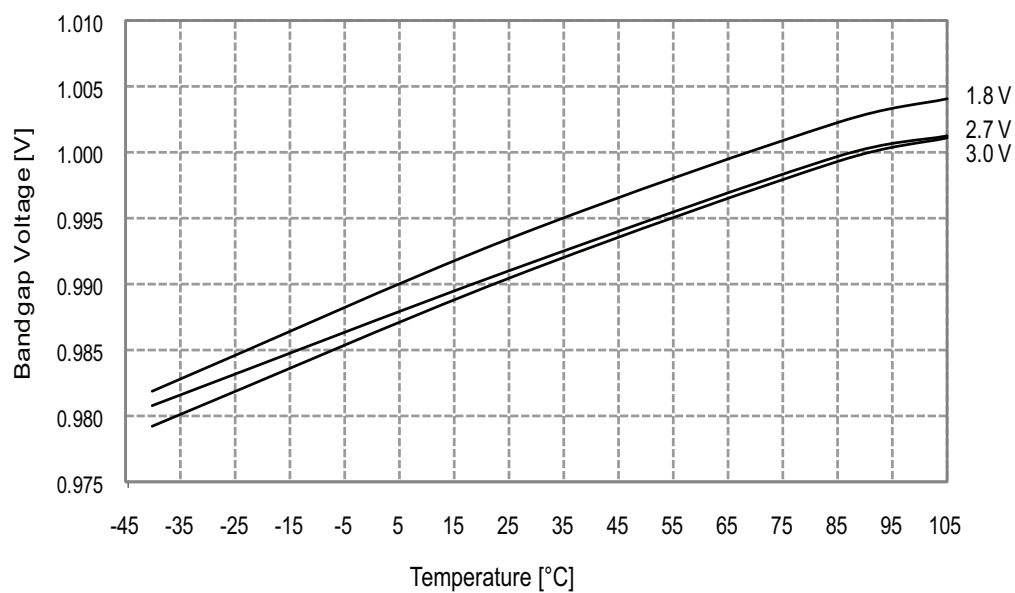
**Figure 33-116. Voltage Scaler INL vs. SCALEFAC**

$T = 25^{\circ}\text{C}$ ,  $V_{CC} = 3.0\text{V}$



### 33.2.5 Internal 1.0V Reference Characteristics

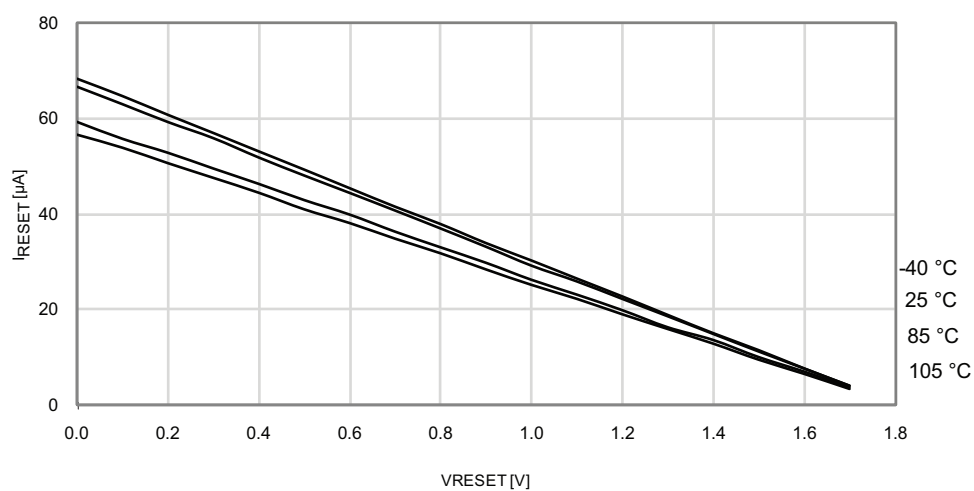
**Figure 33-117. ADC Internal 1.0V Reference vs. Temperature**





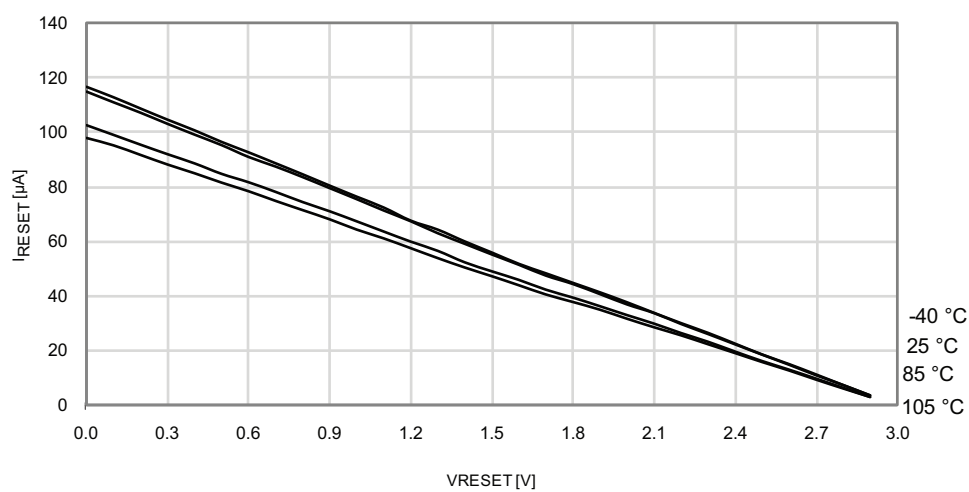
**Figure 33-191. Reset Pin Pull-up Resistor Current vs. Reset Pin Voltage**

$V_{CC} = 1.8V$

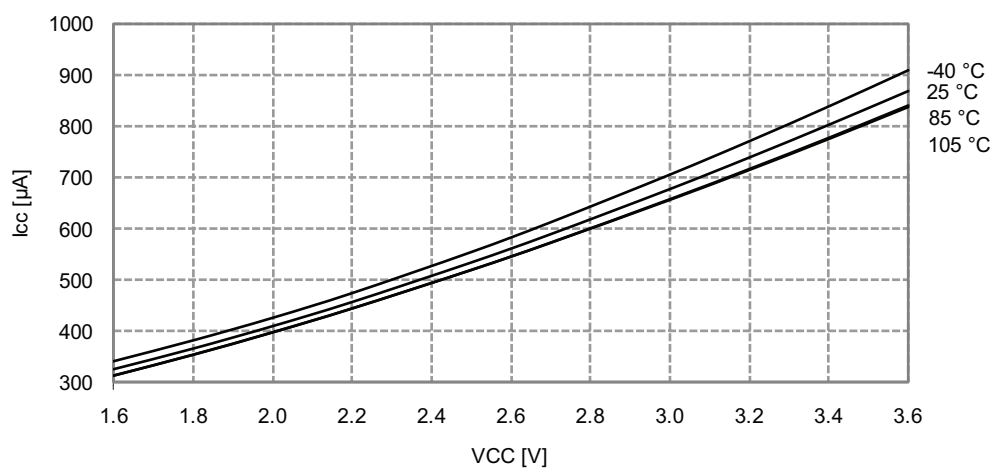


**Figure 33-192. Reset Pin Pull-up Resistor Current vs. Reset Pin Voltage**

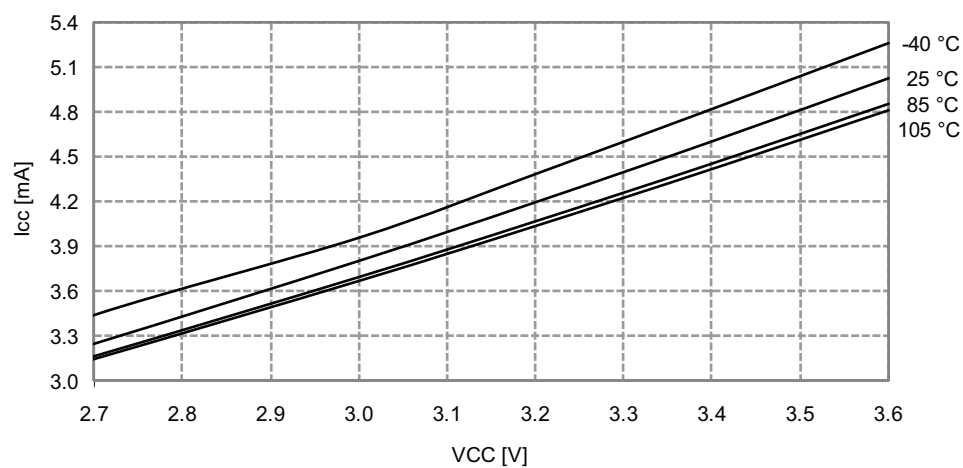
$V_{CC} = 3.0V$



**Figure 33-225. Idle Mode Supply Current vs.  $V_{CC}$**   
 $f_{SYS} = 32\text{MHz}$  internal oscillator prescaled to 8MHz



**Figure 33-226. Idle Mode Current vs.  $V_{CC}$**   
 $f_{SYS} = 32\text{MHz}$  internal oscillator



### 33.4.2.2 Output Voltage vs. Sink/Source Current

Figure 33-233. I/O Pin Output Voltage vs. Source Current

$V_{CC} = 1.8V$

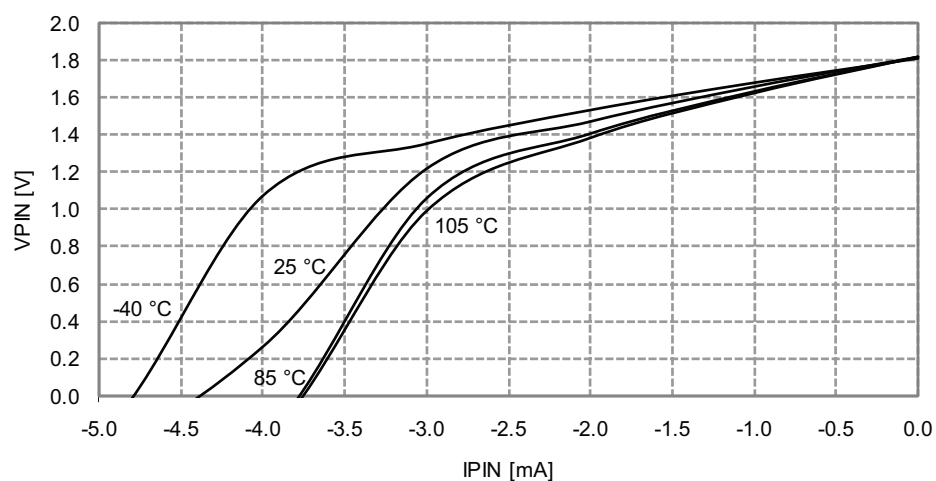
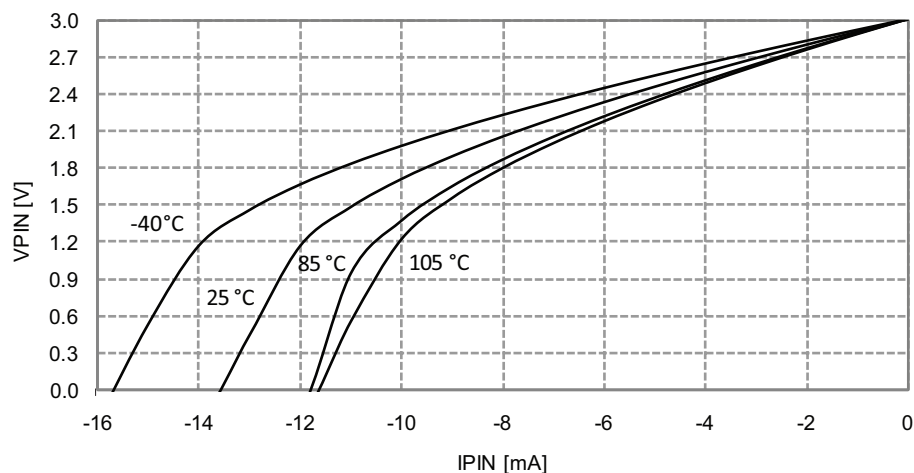


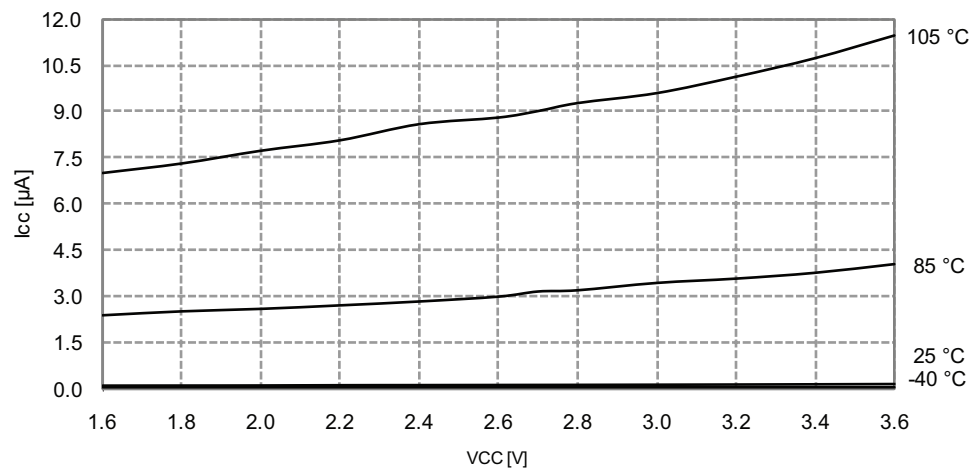
Figure 33-234. I/O Pin Output Voltage vs. Source Current

$V_{CC} = 3.0V$

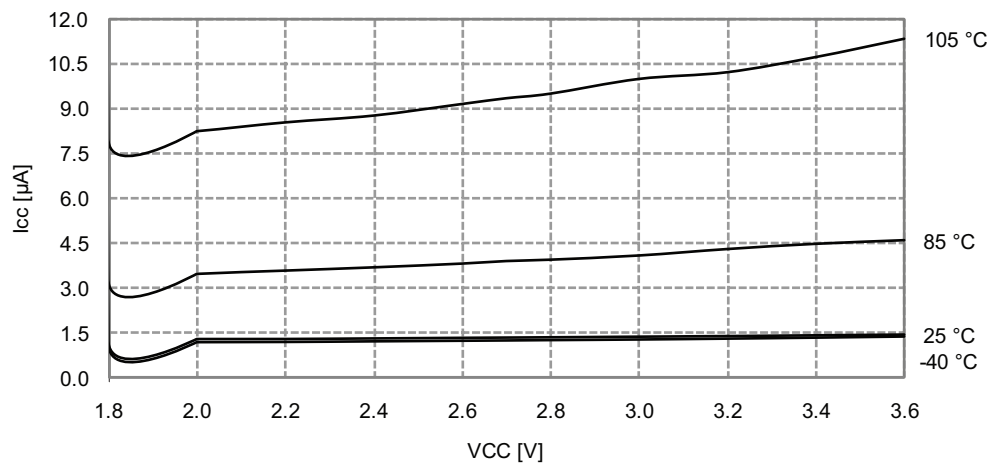


### 33.5.1.3 Power-down Mode Supply Current

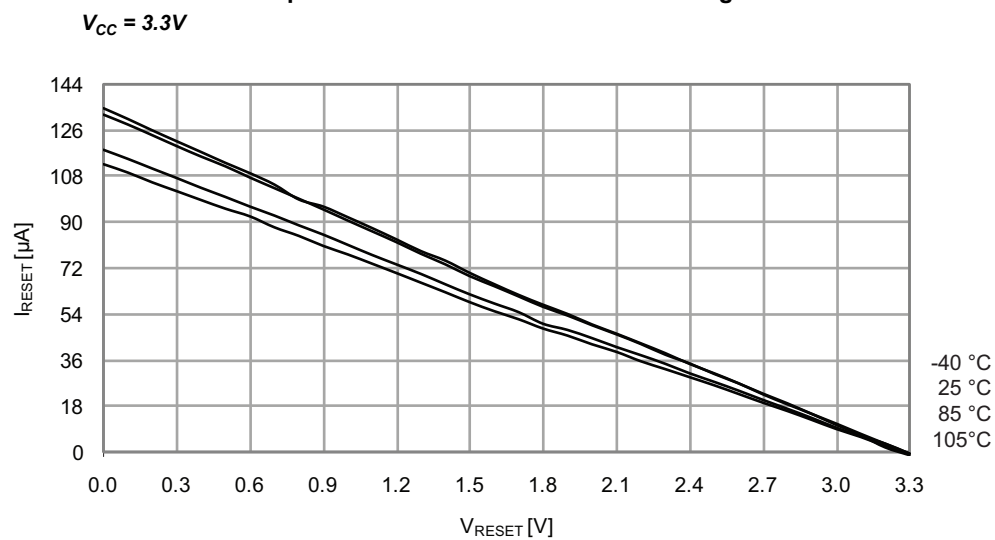
**Figure 33-297. Power-down Mode Supply Current vs.  $V_{CC}$**   
*All functions disabled*



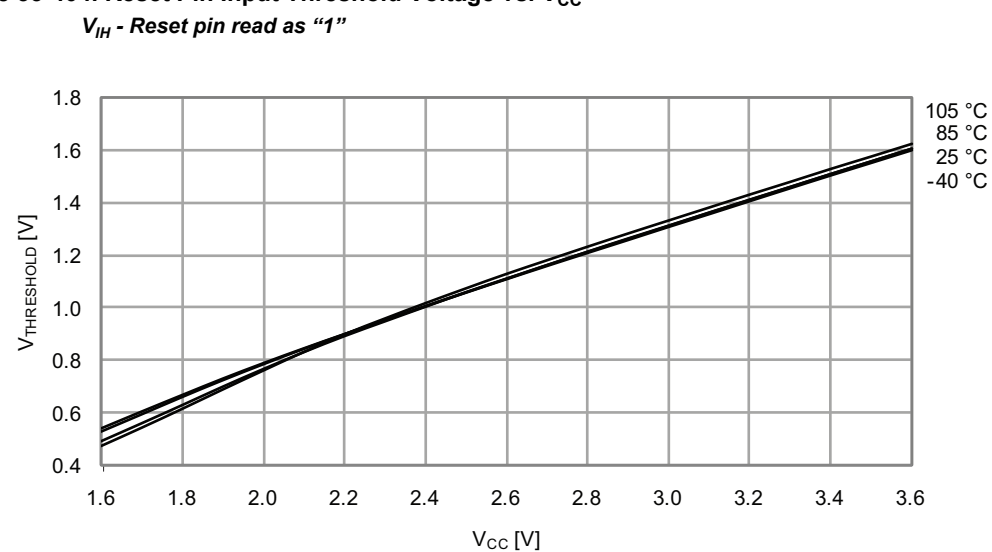
**Figure 33-298. Power-down Mode Supply Current vs.  $V_{CC}$**   
*Watchdog and sampled BOD enabled*



**Figure 33-403. Reset Pin Pull-up Resistor Current vs. Reset Pin Voltage**



**Figure 33-404. Reset Pin Input Threshold Voltage vs.  $V_{CC}$**



- CRC generator module
- ADC 1/2× gain option, and this configuration option in the GAIN bits in the ADC Channel CTRL register
- ADC VCC/2 reference option and this configuration option in the REFSEL bits on the ADC REFCTRL register
- ADC option to use internal Gnd as negative input in differential measurements and this configuration option in the MUXNEG bits in the ADC Channel MUXCTRL register
- ADC channel scan and the ADC SCAN register
- ADC current limitation option, and the CURRLIMIT bits in the ADC CTRLB register
- ADC impedance mode selection for the gain stage, and the IMPMODE bit in the ADC CTRLB register
- Timer/Counter 2 and the SPLITMODE configuration option in the BYTEM bits in the Timer/Counter 0 CTRL register
- Analog Comparator (AC) current output option, and the AC CURRCTRL and CURRCALIB registers
- PORT remap functions with alternate pin locations for Timer/Counter output compare channels, USART0 and SPI, and the PORT REMAP register
- PORT RTC clock output option and the RTCOUT bit in the PORT CLKEVOUT register
- PORT remap functions with alternate pin locations for the clock and event output, and the CLKEVPIN bit in the PORT CLKEVOUT register
- TOSC alternate pin locations, and TOSCSEL bit in FUSEBYTE2
- Real Time Counter clock source options of external clock from TOSC1, and 32.768kHz from TOSC, and 32.768kHz from the 32.768kHz internal oscillator, and these configuration options in the RTCSRC bits in the Clock RTCTRL register
- PLL divide by two option, and the PLLDIV bit in the Clock PLLCTRL register
- PLL lock detection failure function and the PLLDIF and PLLFDEN bits in the Clock XOSCFail register
- The high drive option for external crystal and the XOSCPWR bit on the Oscillator XOSCCTRL register
- The option to enable sequential startup of the analog modules and the ANAINIT register in MCU Control memory

**Problem fix/workaround**

None.

**27. Sampled BOD in Active mode will cause noise when bandgap is used as reference**

Using the BOD in sampled mode when the device is running in Active or Idle mode will add noise on the bandgap reference for ADC, DAC and Analog Comparator.

**Problem fix/workaround**

If the bandgap is used as reference for either the ADC, DAC and Analog Comparator, the BOD must not be set in sampled mode.

**28. Temperature sensor not calibrated**

Temperature sensor factory calibration not implemented.

**Problem fix/workaround**

None.

**28. Disabling of USART transmitter does not automatically set the TxD pin direction to input**

If the USART transmitter is idle with no frames to transmit, setting TXEN to zero will not automatically set the TxD pin direction to input.

### Problem fix/workaround

Check if the bus state is IDLE. If this is the case, it is safe to clear APIF. If the bus state is not IDLE, wait for the SCL pin to be low before clearing APIF.

#### Code:

```
/* Only clear the interrupt flag if within a "safe zone". */
while ( /* Bus not IDLE: */
        ((COMMS_TWI.MASTER.STATUS & TWI_MASTER_BUSSTATE_gm) !=
         TWI_MASTER_BUSSTATE_IDLE_gc) &&
        /* SCL not held by slave: */
        !(COMMS_TWI.SLAVE.STATUS & TWI_SLAVE_CLKHOLD_bm)
      )
{
    /* Ensure that the SCL line is low */
    if ( !(COMMS_PORT.IN & PIN1_bm) )
        if ( !(COMMS_PORT.IN & PIN1_bm) )
            break;
}
/* Check for an pending address match interrupt */
if ( !(COMMS_TWI.SLAVE.STATUS & TWI_SLAVE_CLKHOLD_bm) )
{
    /* Safely clear interrupt flag */
    COMMS_TWI.SLAVE.STATUS |= (uint8_t)TWI_SLAVE_APIF_bm;
}
```

### 22. TWI START condition at bus timeout will cause transaction to be dropped

If Bus Timeout is enabled and a timeout occurs on the same Peripheral Clock cycle as a START is detected, the transaction will be dropped.

#### Problem fix/workaround

None.

### 23. TWI Data Interrupt Flag erroneously read as set

When issuing the TWI slave response command CMD=0b11, it takes one Peripheral Clock cycle to clear the data interrupt flag (DIF). A read of DIF directly after issuing the command will show the DIF still set.

#### Problem fix/workaround

Add one NOP instruction before checking DIF.

### 24. WDR instruction inside closed window will not issue reset

When a WDR instruction is execute within one ULP clock cycle after updating the window control register, the counter can be cleared without giving a system reset.

#### Problem fix/workaround

Wait at least one ULP clock cycle before executing a WDR instruction.

### 34.5.5 Rev. E

- Bandgap voltage input for the ACs can not be changed when used for both ACs simultaneously
- $V_{CC}$  voltage scaler for AC is non-linear
- ADC gain stage cannot be used for single conversion
- ADC has increased INL error for some operating conditions
- ADC gain stage output range is limited to 2.4V
- ADC Event on compare match non-functional
- ADC propagation delay is not correct when  $8\times - 64\times$  gain is used
- Bandgap measurement with the ADC is non-functional when  $V_{CC}$  is below 2.7V
- Accuracy lost on first three samples after switching input to ADC gain stage
- Configuration of PGM and CWCM not as described in the XMEGA D Manual
- PWM is not restarted properly after a fault in cycle-by-cycle mode
- BOD will be enabled at any reset
- EEPROM page buffer always written when NVM DATA0 is written
- Pending full asynchronous pin change interrupts will not wake the device
- Pin configuration does not affect Analog Comparator Output
- NMI Flag for Crystal Oscillator Failure automatically cleared
- RTC Counter value not correctly read after sleep
- Pending asynchronous RTC-interrupts will not wake up device
- TWI Transmit collision flag not cleared on repeated start
- Clearing TWI Stop Interrupt Flag may lock the bus
- TWI START condition at bus timeout will cause transaction to be dropped
- TWI Data Interrupt Flag (DIF) erroneously read as set
- WDR instruction inside closed window will not issue reset
- Non available functions and options
- Sampled BOD in Active mode will cause noise when bandgap is used as reference
- Temperature sensor not calibrated
- Disabling the USART transmitter does not automatically set the TxD pin direction to input

#### 1. Bandgap voltage input for the ACs cannot be changed when used for both ACs simultaneously

If the Bandgap voltage is selected as input for one Analog Comparator (AC) and then selected/deselected as input for another AC, the first comparator will be affected for up to 1 $\mu$ s and could potentially give a wrong comparison result.

##### **Problem fix/workaround**

If the Bandgap is required for both ACs simultaneously, configure the input selection for both ACs before enabling any of them.

#### 2. $V_{CC}$ voltage scaler for AC is non-linear

The 6-bit  $V_{CC}$  voltage scaler in the Analog Comparators is non-linear.



## **16. NMI Flag for Crystal Oscillator Failure automatically cleared**

NMI flag for Crystal Oscillator Failure (XOSCFDIF) will be automatically cleared when executing the NMI interrupt handler.

### **Problem fix/workaround**

This device revision has only one NMI interrupt source, so checking the interrupt source in software is not required.

## **17. Writing EEPROM or Flash while reading any of them will not work**

The EEPROM and Flash cannot be written while reading EEPROM or Flash, or while executing code in Active mode.

### **Problem fix/workaround**

Enter IDLE sleep mode within 2.5 $\mu$ s (five 2MHz clock cycles and 80 32MHz clock cycles) after starting an EEPROM or flash write operation. Wake-up source must either be EEPROM ready or NVM ready interrupt. Alternatively set up a Timer/Counter to give an overflow interrupt 7ms after the erase or write operation has started, or 13ms after atomic erase-and-write operation has started, and then enter IDLE sleep mode.

## **18. RTC Counter value not correctly read after sleep**

If the RTC is set to wake up the device on RTC Overflow and bit 0 of RTC CNT is identical to bit 0 of RTC PER as the device is entering sleep, the value in the RTC count register can not be read correctly within the first prescaled RTC clock cycle after wakeup. The value read will be the same as the value in the register when entering sleep.

The same applies if RTC Compare Match is used as wake-up source.

### **Problem fix/workaround**

Wait at least one prescaled RTC clock cycle before reading the RTC CNT value.

## **19. Pending asynchronous RTC-interrupts will not wake up device**

Asynchronous Interrupts from the Real-Time-Counter that is pending when the sleep instruction is executed, will be ignored until the device is woken from another source or the source triggers again.

### **Problem fix/workaround**

None.

## **20. TWI Transmit collision flag not cleared on repeated start**

The TWI transmit collision flag should be automatically cleared on start and repeated start, but is only cleared on start.

### **Problem fix/workaround**

Clear the flag in software after address interrupt.

## **21. Clearing TWI Stop Interrupt Flag may lock the bus**

If software clears the STOP Interrupt Flag (APIF) on the same Peripheral Clock cycle as the hardware sets this flag due to a new address received, CLKHOLD is not cleared and the SCL line is not released. This will lock the bus.